

## Description

The AH4930Q automotive 3D magnetic chip is a miniature monolithic sensor IC sensitive to the three orthogonal components of the flux density applied to the IC. On-chip integrated temperature sensor data is available for system functions such as junction temperature indication and temperature compensation of magnetic field measurement. A precision analog signal-path along with integrated ADC digitizes the measured analog magnetic field values, and this allows the AH4930Q with the correct magnetic circuit to decode the absolute position of any moving magnet. With its magnetic field detection in x, y, and z-direction the sensor reliably measures three-dimensional, linear and rotation movements.

The AH4930Q measurement data can be read over I<sup>2</sup>C bus. The sensor is runtime programmable and offers on-chip temperature compensation of the measured units. The selectable power mode control unit enables micro-power and continuous measurement functionality. Applications include joysticks, control elements (white goods, multifunction knobs), or electric meters (anti-tampering) and any other application that requires accurate angular measurements or low power consumptions.

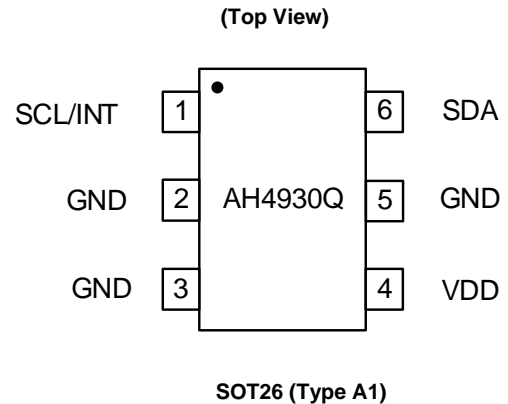
## Features

- 3D magnetic flux density sensing
- Low power-down current 9nA typical
- Very low power consumption = 13µA during operation (10Hz, typ)
- Digital output via standard I<sup>2</sup>C interface up to 1 Mbit/sec
- 12-bit data resolution for each measurement direction
- Bx, By and Bz linear field measurement up to +1300Gs
- Different power modes and variable update frequencies
- Supply voltage range = 2.8V to 5.5V, temperature range T<sub>J</sub> = -40°C to +125°C
- Small, industrial 6-pin SOT26 (Type A1) package
- Interrupt signal available to wake up a microcontroller to save system power and watch dog in wake-up mode
- Temperature measurement
- **Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)**
- **Halogen and Antimony Free. "Green" Device (Note 3)**
- **The AH4930Q is suitable for automotive applications requiring specific change control; this part is AEC-Q100 qualified, PPAP capable, and manufactured in IATF16949 certified facilities.**

<https://www.diodes.com/quality/product-definitions/>

- Notes:
1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
  2. See <https://www.diodes.com/quality/lead-free/> for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
  3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

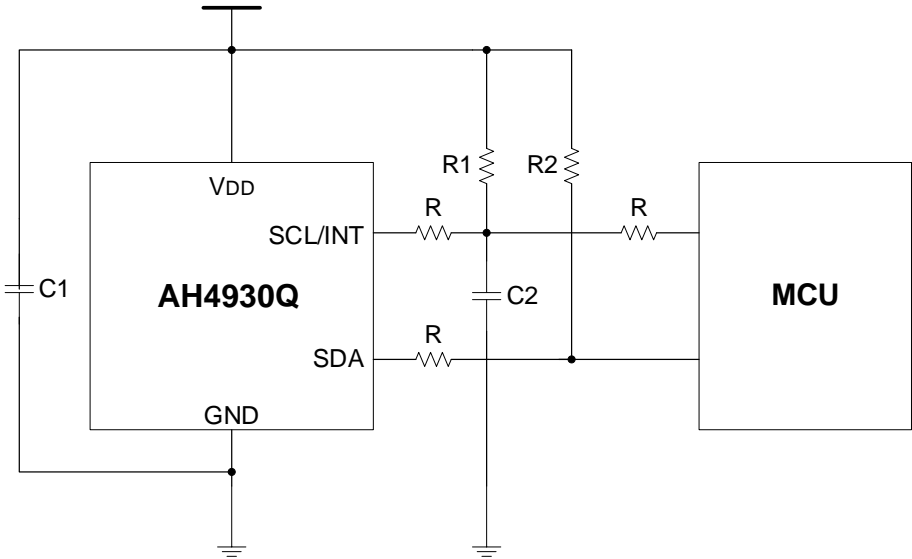
## Pin Assignments



## Applications

- Knobs/levers
- Joysticks with push
- Rotaries with push
- Linear (long strokes)
- Stalk gear shifters
- Shifter position sensors
- Robotics shaft positions
- Flap positions
- Mirror positions
- Flow meters
- Load detection
- Water levels
- Multimedia rotaries/push selectors
- Door handles & door locks
- Motor commutation
- Power tools (speed, torque, direction selections)
- 2-wheelers (throttle controls, multifunction switchgears)

**Typical Applications Circuit** (Note 4)



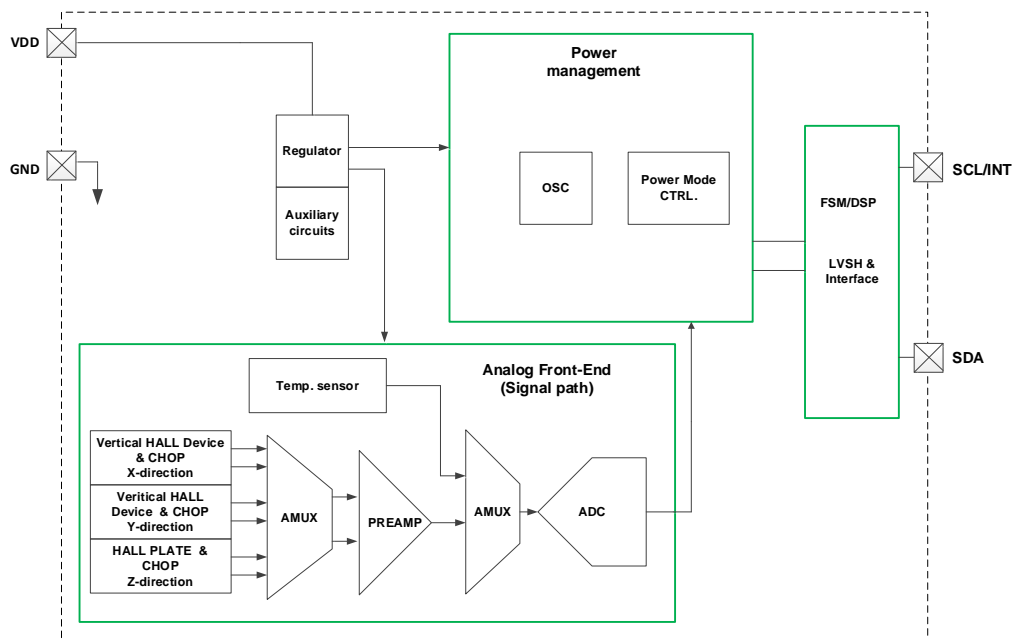
Note: 4. C1 = 100nF, R1/R2 = 1.2kΩ are recommended by Diodes Incorporated. R/C2 values are dependent on capability of noise immunity.

**Pin Descriptions**

Package: SOT26 (Type A1)

Pin Number	Pin Name	I/O	Function
1	SCL/INT	I/O	Bus clock, also used as INT output.
2	GND	Ground	IC ground
3	GND	Ground	Not used, should be Grounded.
4	VDD	Power	Power
5	GND	Ground	Not used, should be Grounded.
6	SDA	I/O	Bus data

**Functional Block Diagram**



**Absolute Maximum Ratings** (Note 5) (@T<sub>A</sub> = +25°C, 10G = 1mT, unless otherwise specified.)

Symbol	Parameter	Value	Unit
V <sub>DD</sub>	Supply Voltage (Notes 5, 6)	6	V
V <sub>DD_REV</sub>	Reverse Supply Voltage	-0.3	V
SDA, SCL	Voltage on SDA, SCL	-0.3 to +6	V
B	Magnetic Flux Density	10000	G
P <sub>D</sub>	Package Power Dissipation (Note 7)	SOT26 (Type A1) 1150	mW
T <sub>STG</sub>	Storage Temperature Range	-65 to +125	°C
T <sub>J</sub>	Maximum Junction Temperature	+150	°C
ESD	Human Body Model ESD Capability (Note 8)	2	kV
	Charge Device Model ESD Capability (Note 8)	1000	V

- Notes:
- Stresses greater than those listed under *Absolute Maximum Ratings* can cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to *Absolute Maximum Ratings* for extended periods can affect device reliability.
  - The absolute maximum V<sub>DD</sub> of 6V is a transient stress rating and is not meant as a functional operating condition. It is not recommended to operate the device at the absolute maximum rated conditions for any period of time.
  - Device mounted on the JEDEC High-K board. 3 inch x 3 inch with 1oz. Internal power and ground planes and 2oz. copper traces on the top and bottom of the board.
  - This device is ESD sensitive.

### Recommended Operating Conditions (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Symbol	Parameter	Conditions	Rating	Unit
V <sub>DD</sub>	Supply Voltage	Operating	2.8 to 5.5	V
T <sub>J</sub>	Operating Temperature Range	Operating	-40 to +125	°C

### Electrical Characteristics (V<sub>DD</sub> = 3.3V @T<sub>A</sub> = +25°C, unless otherwise specified.)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V <sub>DD</sub>	Supply voltage	—	2.8	3.3	5.5	V
t <sub>PUP</sub>	Power-up ramp time	V <sub>DD</sub> rising from 0 to 90% of V <sub>DD</sub>	—	—	10	µs
t <sub>INIT</sub>	Sensor initialization time	Power-up reset to first I <sup>2</sup> C cycle	500	—	—	µs
V <sub>OUS</sub>	Power-up over-undershoot	Envelope which must not be exceeded at the end of a power-up	3	3.3	3.5	V
V <sub>UVLO</sub>	Reset level (UVLO)	V <sub>DD</sub> rising to start conversion	—	2.5	—	V
V <sub>UVLO_HYS</sub>	Reset level_hysteresis (UVLO)	V <sub>UVLO</sub> (V <sub>IN</sub> falling to stop conversion)	—	0.1	—	V
I <sub>DD(ULMP)</sub>	I <sub>DD</sub> in duty cycled operation average current	Ultra low-power mode	—	13 (10Hz)	—	µA
I <sub>DD(LPM)</sub>	I <sub>DD</sub> in duty cycled operation average current	Low-power mode	—	95 (83.3Hz)	—	µA
I <sub>DD(FSM)</sub>	I <sub>DD</sub> in continuous operation average current	Fast mode	—	3.8 (3.3kHz)	—	mA
I <sub>DD(POWER-DOWN)</sub>	I <sub>DD</sub> in power-down mode	IC is in power-down condition	—	9	—	nA
V <sub>IL</sub>	Input low threshold voltage	All input pins	—	—	0.3	V <sub>DD</sub>
V <sub>IH</sub>	Input high threshold voltage	All input pins	0.7	—	—	V <sub>DD</sub>
V <sub>L_HYS</sub>	Input hysteresis voltage	All input pins	—	0.05	—	V
V <sub>OL</sub>	Output low level	V <sub>OL</sub> (@3mA)	—	—	0.4	V
V <sub>OH</sub>	Output high level	Given by ext. pullup resistor 1.2kΩ	—	V <sub>DD</sub>	—	V
I <sub>LEAKAGE</sub>	I <sub>LEAKAGE</sub> when pin disabled	SDA, SCL	—	—	0.1	µA
T <sub>RANGE</sub>	Temp. sensor (range)	—	-40	—	+125	°C
T <sub>25</sub>	Temp. sensor +25°C code	T <sub>A</sub> = +25°C	—	25	—	LSB
T <sub>RES</sub>	Temp. sensor (resolution 12bits)	—	—	1	—	°C /LSB
T <sub>ACC</sub>	Temp. sensor (accuracy)	T <sub>A</sub> = +25°C	—	+/-10	—	°C
f <sub>UR</sub>	Update rate X, Y, Z	Max. conversion rate (Fast mode)	—	3.3k	—	Hz
f <sub>UR_LP</sub>	Update rate (Low power)	INT. triggered rate in LPM	—	83.3	—	Hz
f <sub>UR_ULP</sub>	Update rate (Ultra LP)	INT. triggered rate in ULPM	—	10	—	Hz
t <sub>CLK_E</sub>	Clock freq. drift	Freq. shift of int. clock (T <sub>A</sub> = -40°C to +125°C)	-20	0	20	%
t <sub>INT</sub>	End of conversion (INT pulse)	Low active pulse width	1.5	2	—	µs

**Electrical Characteristics** ( $V_{DD} = 3.3V$  @  $T_A = +25^\circ C$ , unless otherwise specified.) (continued)

**Timing Requirements for I<sup>2</sup>C:**

Symbol	Parameter	400kHz (Fast Mode)			1000kHz (Fast Mode+)			Unit
		Min	Typ	Max	Min	Typ	Max	
f <sub>SCL</sub>	I <sup>2</sup> C clock frequency	—	—	400	—	—	1000	kHz
t <sub>L</sub>	Clock low time	1.3	—	—	0.5	—	—	μs
t <sub>H</sub>	Clock high time	0.6	—	—	0.4	—	—	μs
t <sub>STA</sub>	Hold time for a (repeated) START condition	0.6	—	—	0.4	—	—	μs
t <sub>STOP</sub>	Setup time for STOP condition	0.6	—	—	0.4	—	—	μs
t <sub>SU</sub>	Data setup time	0.1	—	—	0.1	—	—	μs
t <sub>HOLD</sub>	Data hold time	0	—	—	0	—	—	μs
t <sub>RISE</sub>	Rise time of SDA and SCL (Note 9)	—	—	0.5	—	—	0.5	μs
t <sub>FALL</sub>	Fall time of SDA and SCL (Note 9)	—	—	0.3	—	0.25	0.3	μs
t <sub>WAIT</sub>	Bus free time between a STOP and a START condition	0.6	—	—	0.4	—	—	μs

Note: 9. Dependent on used R-C combination. For applications, total capacitive load should be < 200pF.

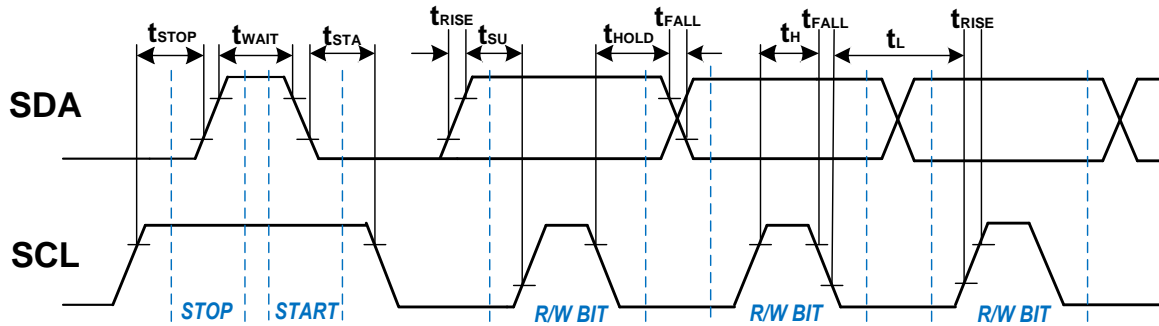
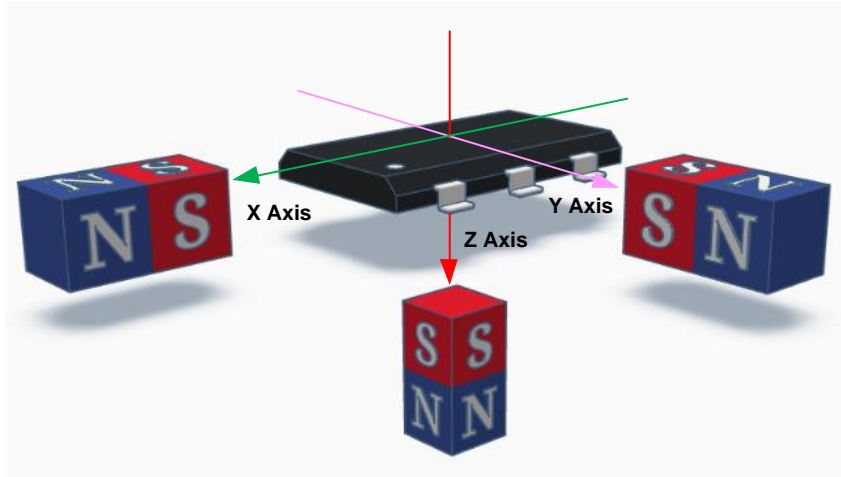


Figure 1. I<sup>2</sup>C Timing Parameters

**Magnetic Characteristics** (Notes 10 and 11) ( $T_A = +25^\circ\text{C}$ ,  $V_{DD} = 3.3\text{V}$ , unless otherwise specified.)

Standard convention for representing the direction of magnetic field strength and flux density by positive and negative signs is as follows:

A positive field is considered as South-Pole facing the corresponding Hall element and Figure 2 shows the definition of magnetic directions X, Y, Z of the AH4930Q



**Figure 2. Definition of Magnetic Field Direction**

( $V_{DD} = 3.3\text{V}$  @  $T_A = +25^\circ\text{C}$ , unless otherwise specified. Magnetic range =  $\pm 1300$  Gauss)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
Bxyz_lin (Note 12)	Usable linear magnetic range	Bx, By, Bz	—	$\pm 1300$	—	Gauss
Bo_xy	Offset	Bx, By	-15	+2	15	Gauss
Bo_z	Offset	Bz	-10	+2	10	Gauss
Sx, Sy, Sz	Sensitivity X, Y, Z	Bx, By, Bz	—	1	—	LSB/G
Res12	Resolution 12bit	—	—	1	—	G/LSB
Bn	Magnetic noise (rms = 1 sigma)	Bx, By, Bz	—	1	—	Gauss

- Notes:
- 10. Typical data is at  $T_A = +25^\circ\text{C}$ ,  $V_{DD} = 3.3\text{V}$ .
  - 11. Maximum and minimum parameter values over operating temperature range are not tested in production; they are guaranteed by design. The magnetic characteristics may vary with supply, operating temperature and after soldering.
  - 12. Not subject to production test, verified by design/characterization.

**Magnetic Characteristics** ( $V_{DD} = 3.3V$  @ $T_A = -40^{\circ}C$  to  $+125^{\circ}C$ , unless otherwise specified.)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
SxD, SyD, SzD	Sensitivity drift	Sx, Sy, Sz	—	+/-20	—	%
Bo_D_xy (Note 12)	Offset drift	Bx, By @0Gs	-15	+/-2	+15	Gauss
Bo_D_z (Note 12)	Offset drift	Bz @0Gs	-10	+/-2	+10	Gauss
Mxy_D (Note 12)	X to Y magnetic matching drift	—	—	+/-5	—	%
Mx/yz_D (Note 12)	X/Y to Z magnetic matching drift	—	—	+/-20	—	%
TC	Temperature compensation	Bx, By, Bz	—	0	—	ppm/K
DNL (Note 12)	Differential nonlinearity	Bx, By, Bz	—	+/-5	—	LSB
INL (Note 12)	Integral nonlinearity	Bx, By, Bz	—	0.1	—	%FSR

Note: 12. Not subject to production test, verified by design/characterization.

Equation for parameter “X to Y magnetic matching”:

$$M_{XY} = 100 * 2 * \frac{S_x - S_y}{S_x + S_y} [\%]$$

Equation for parameter “X/Y to Z magnetic matching”:

$$M_{X/YZ} = 100 * 2 * \frac{S_x + S_y - 2 * S_z}{S_x + S_y + 2 * S_z} [\%]$$

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## Application Information

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### 1 General Description

As described on the block diagram the three vector components of the magnetic flux density (BX, BY and BZ) applied to the IC are sensed through the sensor front-end. The 3-axes Hall signals are generated at the Hall plates and amplified. The analog front-end is based on a fully differential analog chain with offset cancellation technique. The conditioned analog signals are converted through an ADC and provided to a DSP block for further processing. The DSP stage is a customized finite state machine whose major function consists of signal conditioning of the XYZ Hall signals. Offset and sensitivity drift compensation are using the calibrated internal temperature sensor to improve the sensor's accuracy.

These 3D linear Hall measurements can be read out to the communication bus master. The supported communication protocols are I<sup>2</sup>C, where the AH4930Q is a slave on the bus. Upon read-back, it is then up to the microcontroller to process the measurement data in order to achieve more complex position sensing functionality required by the application.

### 2 Functional Description

The AH4930Q consists of three main function blocks containing:

- The power management system: containing a low-power oscillator, a fast oscillator, biasing, accurate reset, and undervoltage detection.
- The analog front-end: containing the HALL biasing, HALL sensing with multiplexers and an ADC. Furthermore, a temperature sensor is implemented.
- The FSM/DSP and I<sup>2</sup>C interface: containing the Finite State Machine and DSP to process data, I<sup>2</sup>C interface to communicate to master, register file to store parameters and I/O pads.

#### 2.1 Power Management

The power management unit provides the conversion modes control in the IC, a power-on reset function and fast/low-power oscillators as clock sources.

It also handles the startup procedure.

- When startup this unit:
  - provides an accurate reset/UVLO detector, activates the biasing, and fast/low oscillator.
  - the applied voltage level on SDA pin must be set to high for I<sup>2</sup>C mode.
  - let sensor enter power-down mode (also can be configured via I<sup>2</sup>C interface).

Note: 13. The sensor enters the power-down mode by default after power-up.

- After AH4930Q re-configured to one of the operating modes a measurement cycle is performed periodically including:
  - qualifies reset/UVLO condition, starts the internal biasing and enables the fast oscillator.
  - enables the HALL biasing and the measurements of the three HALL probe channels sequentially including temperature.
  - enters the configured mode again.

Only if the supply voltage is high enough to be above V<sub>UVLO</sub> measurements are executed, otherwise the reset circuit will halt the state machine until the supply level is reached and continues its operation. The functions are also restarted if a power-on reset event occurs.

#### 2.2 Analog Front-End (Signal Path)

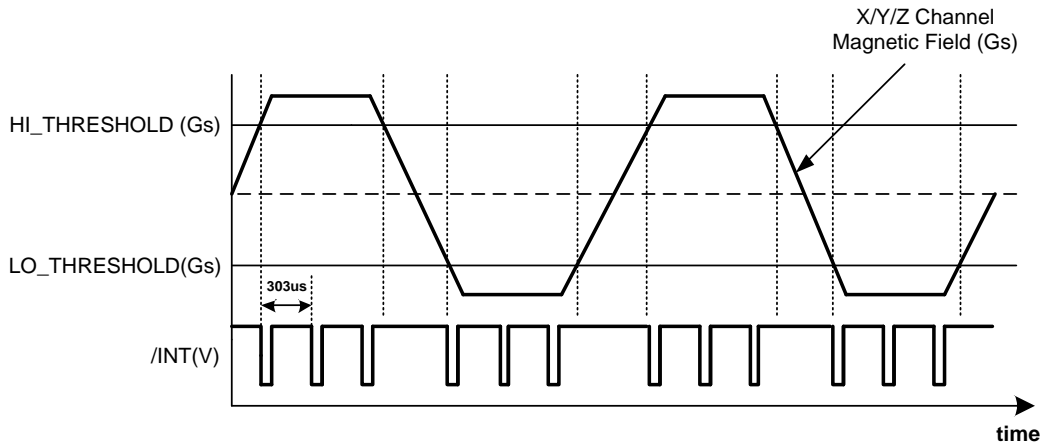
The sensing part of analog front-end performs the measurements of the magnetic field in X, Y and Z direction. Each X, Y and Z-HALL data is consecutively output to a multiplexer, which is then connected to an ADC. The temperature is determined prior to the three HALL channels to compensate sensitivity drift and output as sensed junction temperature.



**Application Information** (continued)

**2.3 Wake-Up Function**

When upper and lower comparison threshold for each of the three magnetic channels (X/Y/Z) of wake-up function and wake-up enable are set, each component of the applied field is compared to the lower and upper threshold. Whenever one of the results is above or below these thresholds, an interrupt pulse /INT is generated. The sensor informs the microcontroller by asserting an interrupt for a certain magnetic field strength change. Only when all components of the magnetic field stay within the envelope, no interrupt signal will be provided. Note that the /INT can also be inhibited during I<sup>2</sup>C activities to avoid activated collision. A wake-up interrupt /INT is the logical OR among all wake-up interrupt envelopes of the three channels. The wake-up threshold levels will be XYZ\_H/L[10:0]\*2 Gauss when wake-up high/low threshold and wake-up enable are set.



**Figure 3. Wake-Up Function**

**3 Measurements**

Below calculations of the magnetic flux and temperatures with 12 bit/8 bit are shown.

**3.1 Calculation of the Magnetic Flux**

The AH4930Q provides the Bx, By and Bz signed values based on Hall probes calculated in 2's complement. The magnetic flux values can be found in the Bx/By/Bz registers of register table. A generic example is calculated next.

**Table 1 Conversion Table for 12 Bit**

	MSB Bit11	Bit10	Bit9	Bit8	Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	LSB Bit0
	-2048	1024	512	256	128	64	32	16	8	4	2	1
e.g.	1	1	1	1	0	0	0	0	1	1	1	1

Example for 12 Bit read-out: 1111 0000 1111:  $-2048 + 1024 + 512 + 256 + 0 + 0 + 0 + 0 + 8 + 4 + 2 + 1 = -241$  LSB

Calculation to Gs:  $-241 \text{ LSB} \times 1 \text{ Gs/LSB} = -241 \text{ Gs}$

**Table 2 Conversion Table for 8 Bit**

	MSB Bit11	Bit10	Bit9	Bit8	Bit7	Bit6	Bit5	Bit4
	-128	64	32	16	8	4	2	1
e.g.	0	1	0	0	1	1	0	1

Example for 8 Bit read-out: 0100 1101:  $0 + 64 + 0 + 0 + 8 + 4 + 0 + 1 = 77$  LSB

Calculation to Gs:  $77 \text{ LSB} \times 16 \text{ Gs/LSB} = 1232 \text{ Gs}$

## Application Information (continued)

### 3.2 Calculation of the Temperature

The AH4930Q also provides the temperature measurement based on a bandgap reference circuit. The temperature value can be found in two registers of register table (register 3H for the MSBs, register 6H for the LSBs).

The temperature is a signed value calculated in 2's complement but it will not provide 8 bit read-out. Examples with 12 bit are as follows.

**Table 3 Conversion Table for 12 Bit**

	MSB Bit11	Bit10	Bit9	Bit8	Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	LSB Bit0
	-2048	1024	512	256	128	64	32	16	8	4	2	1
e.g.	0	0	0	0	0	1	1	0	1	0	1	0

Example for 12 bit read-out: 0000 0110 1010:  $0 + 0 + 0 + 0 + 0 + 64 + 32 + 0 + 8 + 0 + 2 + 0 = 106$  LSB

Calculation to temperature in degrees Celsius:  $106 \text{ LSB} \times 1^\circ\text{C}/\text{LSB} = 106^\circ\text{C}$  (Binary code is the temperature value)

## 4 I<sup>2</sup>C Interface

The AH4930Q uses Inter-Integrated Circuit (I<sup>2</sup>C) as communication interfaces with the microcontroller.

The I<sup>2</sup>C-compatible two-wire serial interface provides access to the programmable functions and registers on the device. This protocol uses a two-wire interface for bi-directional communications between the devices connected to the bus. The two interface lines are the serial data line (SDA) and the serial clock line (SCL). Every device on the bus is assigned a unique address and acts as either a master or a slave. AH4930Q can only be a slave in this sensor application.

### 4.1 I<sup>2</sup>C Interface Description

The I<sup>2</sup>C interface has two main functions in AH4930Q: configuring the sensor and receiving measurement data. Additionally, I<sup>2</sup>C also handles the interrupt via SCL pin.

- The I<sup>2</sup>C interface requires two pins:
  - A serial clock (SCL) input pin. The clock is generated by the microcontroller.
  - A serial data pin (SDA) for in & output (open drain). The microcontroller always initiates and concludes the transaction.
- The data transmission order is Most-Significant Bit (MSB) first, Last-Significant Bit (LSB) last. Data bytes start always with the register address 00H.
- The interface can be accessed in any power mode, even in power-down mode.
- The values of all three axis (Bx, By, Bz) are put in separate registers for I<sup>2</sup>C read-out. After a power-on reset, these registers will read zero.
- Power-on reset initializes registers to default values and UVLO levels which only affects the ADC supply level during a conversion will lead to an ADC cycle resetting only, and the register values will remain as they are. Deep reset levels could result in internal registers corruption and will lead into a full reset to make default values to be reloaded, and a power-on cycle will be executed.
- A full reset can be triggered via I<sup>2</sup>C by sending the address 0x00 to all slaves (sensors). A two-bit frame counter allows to check if the power unit did not initiate a measurement cycle, or the ADC did not complete a new measurement - which means the frame counter does not get incremented.
- An I<sup>2</sup>C write transaction writing all four write registers requires a start condition, 45 bits transfer and a stop condition. At 400 kbit/s this means approximately 113µs.
- An I<sup>2</sup>C read transaction reading the top seven registers (from register 00h to 06h) requires a start condition, 81 bits transfer and a stop condition. At 400 kbit/s this means approximately 203µs.

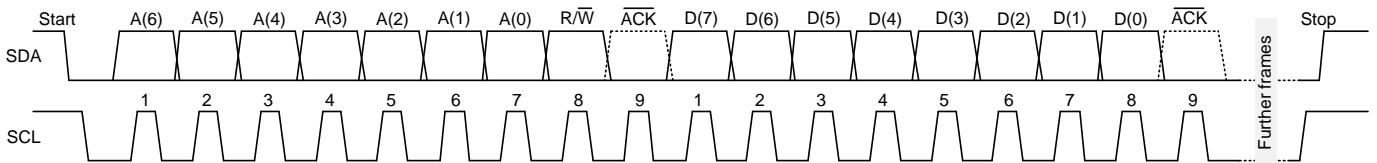
The interface can be operated in I<sup>2</sup>C fast mode (400 kBit/sec max) and is up to 1 Mbit/sec in case the electrical setup of the bus can meet AH4930Q electrical characteristics requirement. The allowed max clock rate above 400kHz has to be defined on demand given a specific electrical setup depending on the parasitic load of the bus line

**Application Information** (continued)

**4.2 I<sup>2</sup>C Format Description**

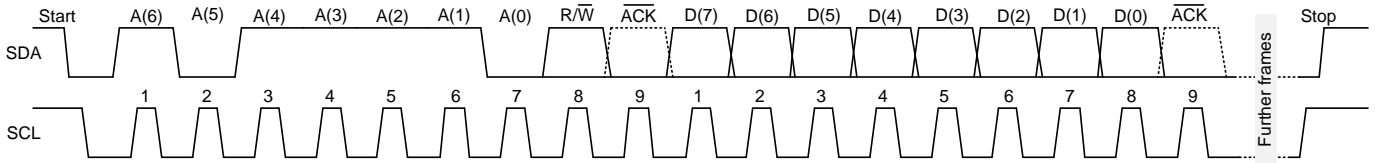
I<sup>2</sup>C transaction is always initiated (with a start condition) and ended (with a stop condition) by the master (microcontroller). During a start or stop condition the SCL line must stay high. The I<sup>2</sup>C transaction frame consists of the start condition, one addressing byte which corresponds to the slave address (sensor number), the data transfer bytes (writing to slave or reading from slave) and finally the stop condition. Addressing and data transfer bytes are always followed by an acknowledge (ACK) bit. During the addressing and the data transfer, bit transitions occur with the SCL line at low. If no error occurs during the data transfer, the ACK bit will be driven low. If an error occurs, the ACK bit will be driven high as NACK.

The I<sup>2</sup>C protocol uses a standard 7-bit address followed by data bytes to be sent or received. AH4930Q does not support 12-bit addressing or any sub-addressing, so each start condition always begins with writing the address, followed by reading (or writing) the first byte of the bitmap and continues with reading (or writing) the next byte until all bytes are read (or written) or the transaction is simply terminated by a stop condition. The basic initiator for the protocol is the falling SDA edge when SCL is high as is called a start condition.



**Figure 4. General I<sup>2</sup>C Format**

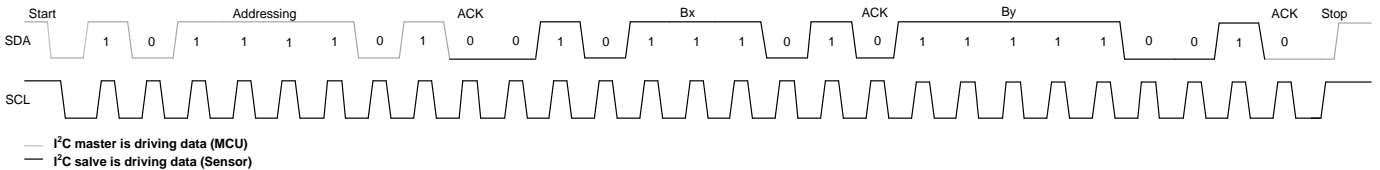
The default setting after startup for a read operation is shown. In order to set SDA must be pulled high during power-up. To set the address the high or low level must be kept 260µs typically after supplying the sensor.



**Figure 5. Read Example with Default Setting (Read = BD; Write = BC)**

**4.3 Communication Examples**

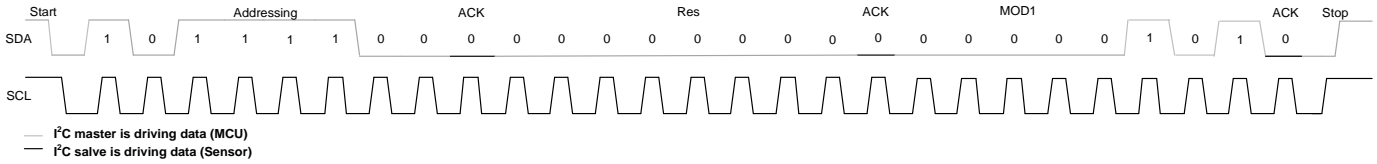
An example of a read transaction is shown in Figure 6. The master generates a start condition followed by the addressing to sensor number (1011110B) and the read bit (1B). The slave responds with an ACK for the addressing and outputs the first register (register 0H), which corresponds to the Bx value (01011101B). The master responds with an ACK once the register is read. The slave outputs the second register (register 1H), which corresponds to the By value (11111001B). The master responds with an ACK and since no more information is required the master generates the stop condition.



**Figure 6. I<sup>2</sup>C Read Transaction Example**

**Application Information** (continued)

An example of a typical write transaction at startup is shown in Figure 7. The AH4930Q is by default configured in power-down and Bx, By, Bz values are zeros. To start Bx, By, Bz conversions at a given update rate the configuration has to be changed to other power mode. In low-power mode example, the master generates a start condition followed by the sensor number (1011110B) and a write bit (0B). The slave responds with an ACK. The master continues the transmission writing 00000000B at the first writing register (a reserved register). The slave responds with an ACK. The master writes 0000 0101B in the second writing register (configuration register MOD1). The slave responds with an ACK and since no more data need to be written the master finishes the transaction with a stop condition. With this configuration the interrupt pulse bit is enabled (MOD1 register = xxxx x1xxB) and the low-power mode bit is enabled (MOD1 register = xxxx xxx1B). Every 10ms a Bx, By, Bz conversion will be measured and once the conversion is completed an interrupt pulse will be sent to master. The master can then read the Bx, By and Bz registers.



**Figure 7. I<sup>2</sup>C Write Transaction Example**

Note: 14. AH4930Q requires 4 write registers be completely written to activate function change.

**5 Power-Up, Sensor Initialization and Access Modes**

At power-up the AH4930Q is initialized with the default configuration and enters power-down mode (default mode). The power-down mode allows master to access the registers to read (default values) or write (for configuration), but no magnetic field nor temperature values are measured.

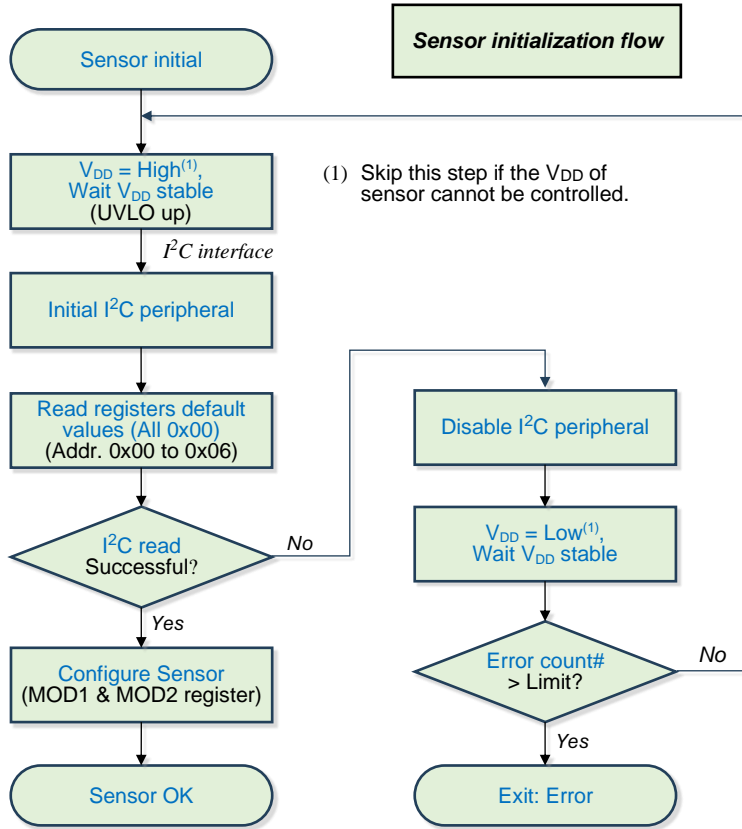
To start measurements, one of the following modes must be configured:

- Continuous (Fast) mode (FSM)
- Low-power mode (LPM)
- Ultra low-power mode (ULPM)
- Master controlled mode (MCM)
- Master controlled low-power mode (programmed by master)

These modes are described in the following sections.

**Application Information** (continued)

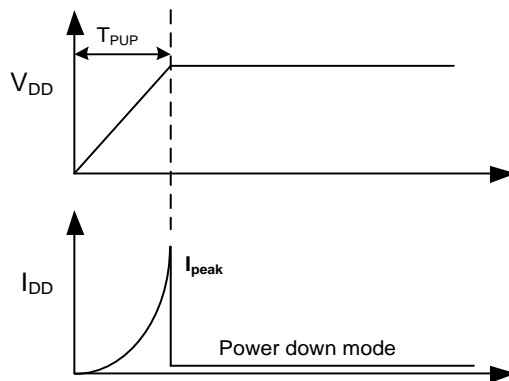
**5.1 Power-Up Sequence and Sensor Initialization**



**5.2 Power-Up and Power-Down Mode**

After power-up, the sensor captures the voltage applied on SDA pin for 260µs to fix I<sup>2</sup>C address. The voltage level on SDA must be high during power-up. For a short period of time the power consumption increases to a larger current. During this short period all functional blocks are active, but no magnetic measurement nor temperature measurement takes place. After AH4930Q enters the “power-down mode” all functional blocks are off and wait for other configurations to leave power-down mode to start measurements.

Note: 15. For startup the sequence in Section 5.1 is strongly recommended.



**Figure 8. Current Consumption During Power-Up**

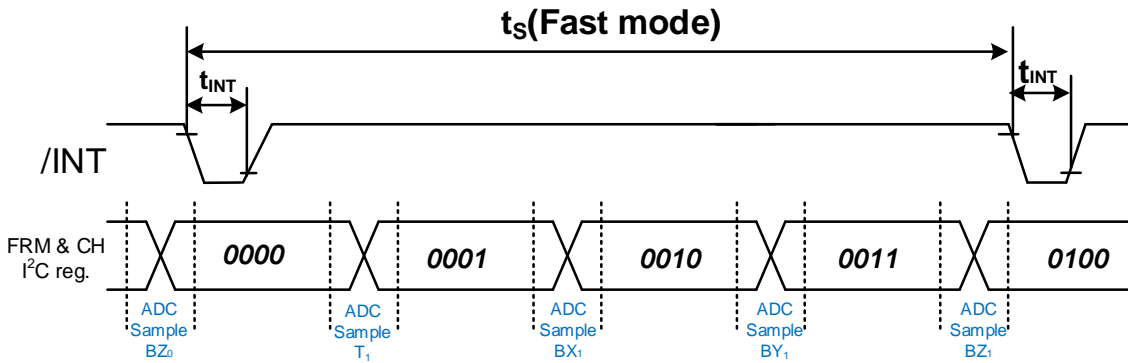
**Application Information** (continued)

**5.2.1 Power-Down Mode (PDM)**

To enter power-down mode, please set in write-register 1H[1] = 0 (FAST = 0) and set 1H[0] = 0 (LOW = 0).

**5.3 Continuous (Fast) Mode (3.3kHz) (FSM)**

Settings: INT = 1, FAST = 1, LOW = 0, LP = 0 (byte settings [hex] = 00, x6, xx, xx)



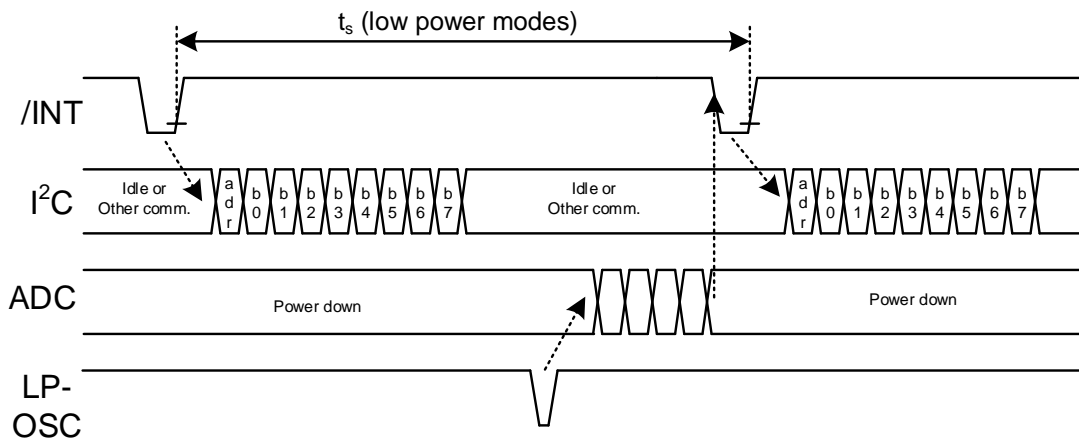
**Figure 9. Fast Mode in Relation to /INT Output**

To optimize the read-out the sample of the last conversion can be read while the next conversion is being performed. The I<sup>2</sup>C read-out speed can be faster or slower than ADC conversion speed depending on the system requirement. Trading between magnet changing speed and system read-out need should be considered.

- Notes: 16. This mode requires an I<sup>2</sup>C fast mode+ 1MHz I<sup>2</sup>C clock to be used to read the data fast enough if system has the need.
- 17. User is recommended to assert I<sup>2</sup>C read transaction as soon as possible after previous /INT assertion to avoid I<sup>2</sup>C transaction being interfered by /INT.

**5.4 Low-Power Mode (83.3Hz) (LPM)**

Settings: INT = 1, FAST = 0, LOW = 1, LP = 1 (byte settings [hex]: 00, x5, xx, 4x)



**Figure 10. Synchronous, Low-Power I<sup>2</sup>C Read-Out Using an /INT Wake-Up Pulse**

In this low-power mode the sensor goes into nearly power-down mode until internal LOSC counter counts up to wake up AH4930Q to perform the next conversion. Once the conversion is completed the interrupt line will be pulled low (if /INT is activated). From above the low-power modes the time window to read out all registers after the rising edge of the interrupt pulse is equal to one over the sample rate of this low-power mode minus the conversion time.

**Application Information** (continued)

**5.4.1 Ultra Low-Power Mode (10Hz) (ULPM)**

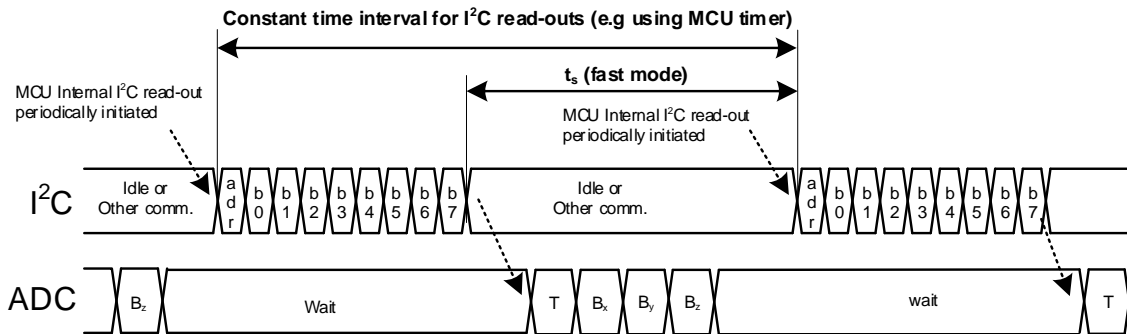
Settings: INT = 1, FAST = 0, LOW = 1, LP = 0 (byte settings [hex]: 00, x5, xx, 0x)

In this mode a very low power combination of ultra low-power consumption and internal regular wake-up function is reached. The basic function is similar to low-power mode, but low-power mode has higher current consumption than ultra low-power mode.

**5.5 Master Controlled Mode (Variable to fmax = 3.3kHz) (MCM)**

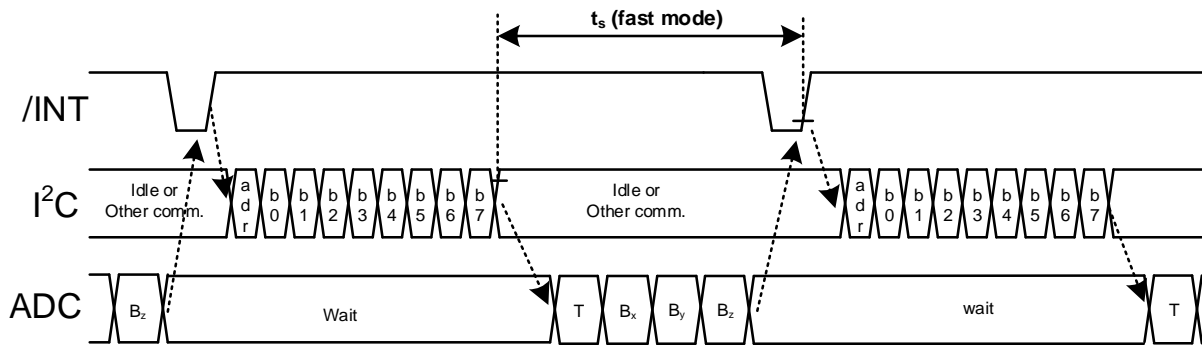
Settings: INT = 0/1, FAST = 1, LOW = 1 (byte settings: 00, x7, xx, xx)

- One measurement cycle is performed, and interrupt is asserted, and the measurement data is available for read-out in the registers.
- The sensor is waiting for read-out and no other measurements are done.
- Once the master performs a read-out a new measurement cycle is internally initiated by the sensor and new values will be stored in the registers. If no further read-out takes place no new measurement cycle is initiated. Periodic read-out of I<sup>2</sup>C causes a re-run of a new measurement cycle. It only needs to be ensured that the read-out time is larger than the time for the I<sup>2</sup>C read frame plus the sensor conversion time.



**Figure 11. Synchronous, Fast I<sup>2</sup>C Access Using a Periodic I<sup>2</sup>C Read-Out**

In the mode the interrupt output could be activated and used as well. This will provide the fastest and safest way to read out all axis data with a 12-bit resolution value, as to be shown next. This allows a read-out of the sensor to the master ( $\mu$ C) using an interrupt service routine. The sample rate is now determined by the ADC conversion time plus the I<sup>2</sup>C read-out time only and fully avoids the read of inconsistent values.



**Figure 12. Synchronous, Fast I<sup>2</sup>C Access Using an /INT Trigger for I<sup>2</sup>C Read-Out**

Note: 18. If user writes registers to set MCM with interrupt enabled and continues to write WU registers, 1 /INT pulse might be omitted if CA bit is set. User can directly read for the first magnetic field data before next /INT asserted.

**Application Information** (continued)

**6 Power Supply Considerations**

The power supply and its circuitries should be designed to ensure a stable startup and sensor initialization as well as a stable operation for correct I<sup>2</sup>C transaction. The sensor can be supplied by the same supply used by the microcontroller or by an alternative supply with switch. The usage of a microcontroller output pin is considered an alternative power supply. The following considerations must be covered in any case:

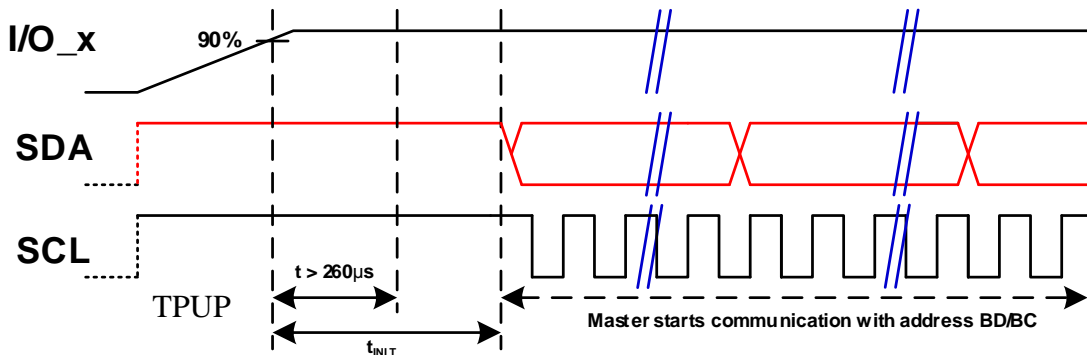
- The voltage on bus pins must not be higher than voltage on the supply pins.
- The supply has to cope with the specified DC currents of the sensor and AC current peaks from digital logic operation (from bus interface and from internal sensor logic).
- Inrush current of the supply buffer capacitor must be considered by dimensioning of the power supply.
- The sensor does not have any internal overvoltage protection nor reverse voltage protection
- The supply power-up ramp is recommended to be as 5.2 specifies.

**7 Bus Configuration with Multiple Sensors**

AH4930Q can be programmed as multiple slaves (sensors, up to 4) to a master in a bus configuration. The slave addresses are configured sequentially at startup. Each slave requires a dedicated supply line, and therefore the master must provide enough I/O pins capable of driving up to 6mA DC in each line.

**7.1 Configuration with Multiple Slaves in I<sup>2</sup>C Interface**

AH4930Q is powered up together with the whole system startup, while AH4930Q remains powered down. Within the first 260µs after the power-up, AH4930Q reads the voltage applied on SDA pin and the voltage level on SDA must be set to high as Figure 13 then the address is set to “1” (default case with open-drain configuration). This configuration remains fixed till the next power-down or reset. Once the slaves are to be configured to multiple sensors as below diagram, the master can access to read or write any slave by addressing them according to Table 4.



**Figure 13. Startup Sequence and Timing for Bus Configuration**

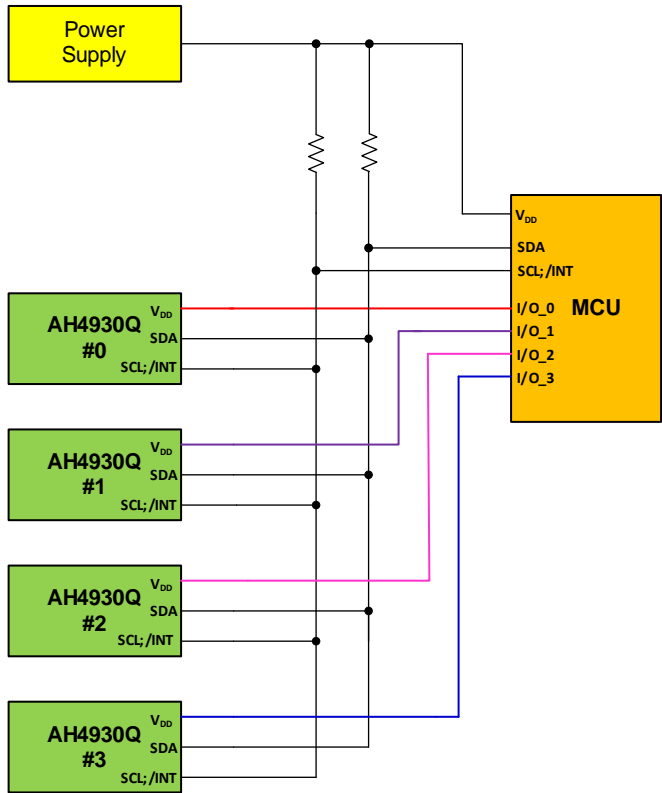
Note: 19. It is also possible to configure multiple slaves by changing the IICAddr bits in the write register MOD1 independently of the SDA pin at startup.

**Table 4 Addressing with Multiple Slaves**

Slave	SDA Pin at Power-Up	IICAddr Bits (Bin)		Read		Write	
		Default	Bus	Bin	Hex	Bin	Hex
0	High (1)	00	11	1001 0101	95	1001 0100	94
1	High (1)	00	10	1001 1101	9D	1001 1100	9C
2	High (1)	00	01	1011 0101	B5	1011 0100	B4
3	High (1)	00	00	1011 1101	BD	1011 1100	BC



**Application Information** (continued)



**Figure 14. Application Circuits for Bus Configuration with Four Slaves**

**8 I<sup>2</sup>C and Registers**

The AH4930Q includes several registers that can be accessed via I<sup>2</sup>C to read data as well as to write and configure settings. There are 16 read registers and 16 write registers. All registers should be accessed from 0H either read or write.

**8.1 Registers Overview**

A register bitmap overview is presented in the tables below. Read registers from 0H to 6H can only be read and cannot be modified via write transactions while write registers 0H to 4H can only be written and cannot be read out via read transactions. 7H to FH can be both written in and read out.

## Application Information (continued)

### 8.1.1 Read Registers

The I<sup>2</sup>C registers can be read at any time, starting always from address 0H and as long as the master sends a clock signal (SCL). It is recommended to use the sensor interrupt to read data after an interrupt pulse. This can avoid reading inconsistent values, especially when running the fast mode. Additionally, several flags can be checked to ensure the data values are consistent and the ADC was not running at the time of read-out.

Read Registers									
Bit	7	6	5	4	3	2	1	0	Comment
Bx(0H)	Bx[11:4]								Bx MSB[11:4]
By(1H)	By[11:4]								By MSB[11:4]
Bz(2H)	Bz[11:4]								Bz MSB[11:4]
Temp(3H)	Temp[11:8]				FRM[1:0]		CH[1:0]		Temp MSB[11:8], Frame number, CH number
Bx2y2(4H)	Bx[3:0]				By[3:0]				Bx LSB[3:0], By LSB[3:0]
Bz2(5H)	Rsvd			PD	Bz[3:0]				PD, Bz LSB[3:0]
Temp2(6H)	Temp[7:0]								Temp LSB[7:0]
WU_XH(7H)	WU_XH[10:3]								WU_X high threshold[10:3]
WU_XL(8H)	WU_XL[10:3]								WU X low threshold[10:3]
WU_YH(9H)	WU_YH[10:3]								WU_Y high threshold[10:3]
WU_YL(AH)	WU_YL[10:3]								WU Y low threshold[10:3]
WU_ZH(BH)	WU_ZH[10:3]								WU_Z high threshold[10:3]
WU_ZL(CH)	WU_ZL[10:3]								WU Z low threshold[10:3]
WU_XLSB(DH)	Rsvd		XL[2:0]			XH[2:0]		WU X high/low threshold[2:0]	
WU_YLSB(EH)	Rsvd		YL[2:0]			YH[2:0]		WU Y high/low threshold[2:0]	
WU_ZLSB(FH)	Rsvd		ZL[2:0]			ZH[2:0]		WU Z high/low threshold[2:0]	
Bx(0H) *) Bx[11:4]: Bx MSB[11:4]									
By(1H) *) By[11:4]: By MSB[11:4]									
Bz(2H) *) Bz[11:4]: Bz MSB[11:4]									
Temp(3H) *) Temp[11:8]: Temp MSB[11:8] *) FRM[1:0]: Frame number. Check if bits have changed in consecutive conversion runs. Increments at every update rate, once a T/X/Y/Z conversion is completed *) CH[1:0]: Channel number. If "00" no conversion (internal power-down) or temperature conversion started (but value not yet stored in the register) If "01" x-direction conversion ongoing If "10" y-direction conversion ongoing If "11" z-direction conversion ongoing									
Bx2y2(4H) *) Bx[3:0]: Bx LSB[3:0] *) By[3:0]: By LSB[3:0]									
Bz2(5H) *) Bz2[4]: PD: Power-down flag. Must be "1" at read-out. If "1", Bx, By, Bz and Temp conversion completed. If "0", Bx, By, Bz and Temp conversion running *) Bz[3:0]: Bz LSB[3:0]									
Temp2(6H) *) Temp[7:0]: Temp LSB[7:0]									
WU(7H-FH) *) WU_XH[10:0]: Wake-up X high threshold[10:0]. Wake-up threshold level = WU_XH[10:0] × 2 gauss. WU_XL[10:0]: Wake-up X low threshold[10:0]. Wake-up threshold level = WU_XL[10:0] × 2 gauss. WU_YH[10:0]: Wake-up Y high threshold[10:0]. Wake-up threshold level = WU_YH[10:0] × 2 gauss. WU_YL[10:0]: Wake-up Y low threshold[10:0]. Wake-up threshold level = WU_YL[10:0] × 2 gauss. WU_ZH[10:0]: Wake-up Z high threshold[10:0]. Wake-up threshold level = WU_ZH[10:0] × 2 gauss. WU_ZL[10:0]: Wake-up Z low threshold[10:0]. Wake-up threshold level = WU_ZL[10:0] × 2 gauss.									

## Application Information (continued)

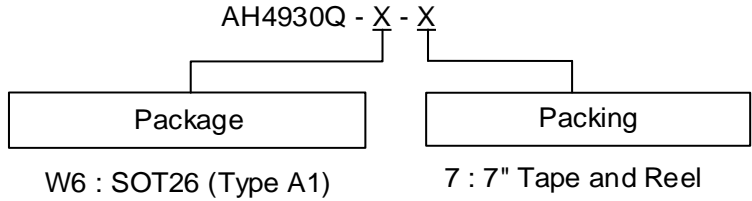
### 8.1.2 Write Registers

Registers will be written starting always from address 0H and as many registers as long as the master generates a clock signal (SCL).

Write Registers									
Bit	7	6	5	4	3	2	1	0	Comment
Rsvd(0H)	Rsvd								Reserved
MOD1(1H)	Rsvd	IICAddr[1:0]		WUE	Rsvd	INT	FAST	LOW	IICAddr, Wake-up enable, INT, Continuous (FAST mode), LOW power mode
Rsvd(2H)	Rsvd								Reserved
MOD2(3H)	Rsvd	LP	Rsvd	CA	Rsvd				Low Power, Collision Avoidance
Rsvd(4H)	Rsvd								Reserved
Rsvd(5H)	Rsvd								Reserved
Rsvd(6H)	Rsvd								Reserved
WU_XH(7H)	WU_XH[10:3]								WU_X high threshold[10:3]
WU_XL(8H)	WU_XL[10:3]								WU X low threshold[10:3]
WU_YH(9H)	WU_YH[10:3]								WU_Y high threshold[10:3]
WU_YL(AH)	WU_YL[10:3]								WU Y low threshold[10:3]
WU_ZH(BH)	WU_ZH[10:3]								WU_Z high threshold[10:3]
WU_ZL(CH)	WU_ZL[10:3]								WU Z low threshold[10:3]
WU_XLSB(DH)	Rsvd	XL[2:0]			XH[2:0]			WU X high/low threshold[2:0]	
WU_YLSB(EH)	Rsvd	YL[2:0]			YH[2:0]			WU Y high/low threshold[2:0]	
WU_ZLSB(FH)	Rsvd	ZL[2:0]			ZH[2:0]			WU Z high/low threshold[2:0]	
<b>MOD1(1H)</b> *) IICAddr[1:0]: I <sup>2</sup> C Address bits: Bits can be set to "00", "01", "10" or "11" to define the slave address in bus configuration *) WUE: Wake-up enable: If "0" disable wake-up function If "1" enable wake-up function *) INT: Interrupt pad enabled: If "1" INT (interrupt pulse) enabled (default). If "0" INT (interrupt pulse) disabled *) FAST: Continuous (Fast) mode If "1" continuous mode enabled If "0" continuous mode disabled *) LOW: Low-power mode If "0" disabled If "1" enabled									
<b>MOD2(3H)</b> *) LP: Low-power period If "0" period is 83ms (ultra low-power period) If "1" period is 10ms *) CA: Collision avoidance. If "0" /INT will be asserted anyway if INT is set to "1" If "1" /INT will be asserted only when I <sup>2</sup> C bus is idle if INT is set to "1"									
<b>WU(7H-FH)</b> *) WU_XH[10:0]: Wake-up X high threshold[10:0]. Wake-up threshold level = WU_XH[10:0] × 2 gauss. WU_XL[10:0]: Wake-up X low threshold[10:0]. Wake-up threshold level = WU_XL[10:0] × 2 gauss. WU_YH[10:0]: Wake-up Y high threshold[10:0]. Wake-up threshold level = WU_YH[10:0] × 2 gauss. WU_YL[10:0]: Wake-up Y low threshold[10:0]. Wake-up threshold level = WU_YL[10:0] × 2 gauss. WU_ZH[10:0]: Wake-up Z high threshold[10:0]. Wake-up threshold level = WU_ZH[10:0] × 2 gauss. WU_ZL[10:0]: Wake-up Z low threshold[10:0]. Wake-up threshold level = WU_ZL[10:0] × 2 gauss.									

Note: 20. Rsvd means reserved. All reserved bits must set to 0.

**Ordering Information**

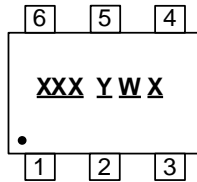


Orderable Part Number	Package Code	Package	Packing	
			Qty.	Carrier
AH4930Q-W6-7	W6	SOT26 (Type A1)	3,000	Tape & Reel

**Marking Information**

SOT26 (Type A1)

**(Top View)**



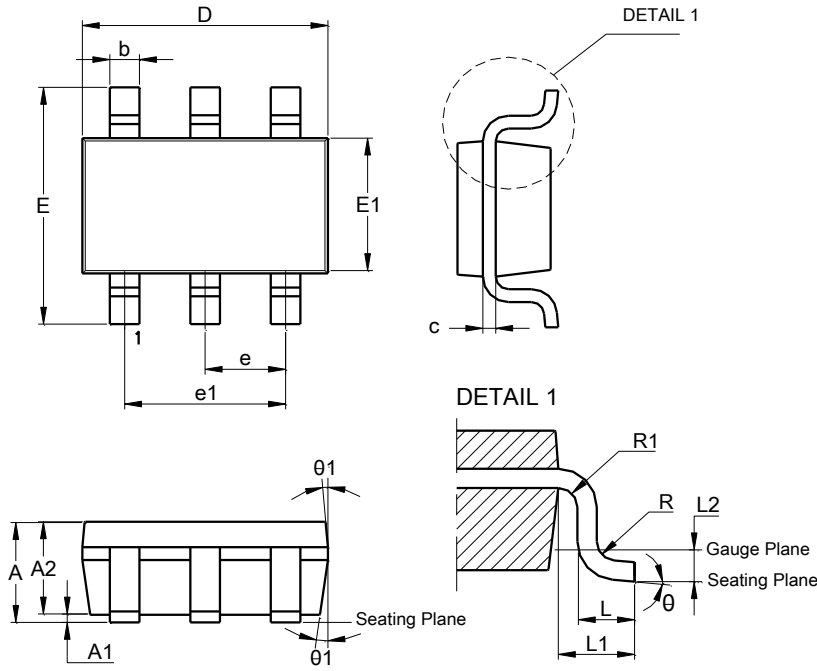
- XXX : Identification Code
- Y : Year 0 to 9 (ex: 5 = 2025)
- W : Week : A to Z : week 1 to 26;  
a to z : week 27 to 52; z represents week 52 and 53
- X : Internal Code

Orderable Part Number	Package	Identification Code
AH4930Q-W6-7	SOT26 (Type A1)	V2Q

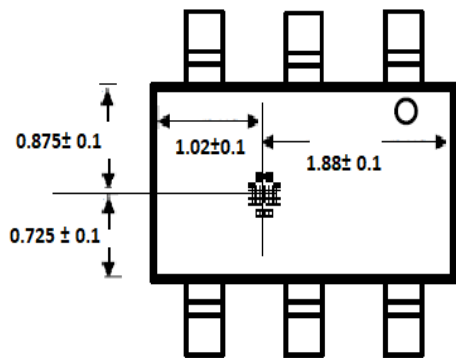
**Package Outline Dimensions**

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

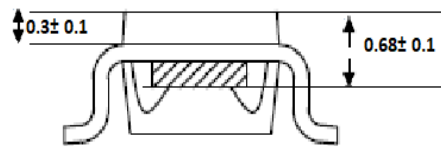
**SOT26 (Type A1)**



SOT26 (Type A1)			
Dim	Min	Max	Typ
A	--	1.45	--
A1	0.00	0.15	--
A2	0.90	1.30	1.15
b	0.30	0.50	--
c	0.08	0.22	--
D	2.90 BSC		
E	2.80 BSC		
E1	1.60 BSC		
e	0.95 BSC		
e1	1.90 BSC		
L	0.30	0.60	0.45
L1	0.60 REF		
L2	0.25 BSC		
R	0.10	--	--
R1	0.10	0.25	--
θ	0°	8°	4°
θ1	5°	15°	10°
<b>All Dimensions in mm</b>			



**Top View**



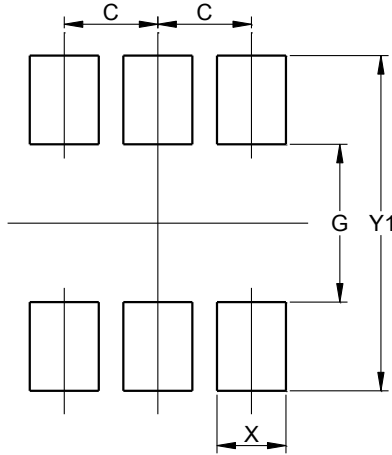
**Side View**

**Sensor Location (Unit: mm)**

**Suggested Pad Layout**

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

**SOT26 (Type A1)**



Dimensions	Value (in mm)
<b>C</b>	0.950
<b>G</b>	1.600
<b>X</b>	0.700
<b>Y</b>	0.900
<b>Y1</b>	3.400

**Mechanical Data**

- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish – Matte Tin Plated Leads, Solderable per MIL-STD-202, Method 208 (E3)
- Weight: 0.016 grams (Approximate)

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